

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/052,032	LUCAST ET AL.
	<b>Examiner</b> Sam Chuan C. Yao	<b>Art Unit</b> 1733

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
see the attached interference search using EAST		7/25/2005	SCY